

Search Notes



Application/Control No.

09/933,285

Examiner

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Applicant(s)/Patent under Reexamination

SMITH ET AL.

Art Unit

3629

SEARCHED

Class	Subclass	Date	Examiner
705	1	9/05	DN
	6		
	7		
	8		
	9		
	10		
	24	✓	✓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
I US	9/05	DN
1. PG pub		
2. Patent		
II FOREIGN		
1. EPO		
2. JPO		
3. Patent		
4. IBM-TDB	✓	✓